35ʳᵈ IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems

Best Paper Award

Preventing Soft-Errors and Hardware Trojans in RISC-V Cores

*Edian Annink, Gerard Rauwerda, Edwin Hakkennes, Alessandra Menicucci, Stefano Di Mascio,
Gianluca Furano and Marco Ottavi*

Best Student Paper Award

Analysis of Proton-induced Single Event Effect in the On-Chip Memory of Embedded Processor

Corrado De Sio, Sarah Azimi, Luca Sterpone and David Merodio Codinachs

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